



Welcome United States Patent and Trademark Office

[Search Results](#)
[BROWSE](#)
[SEARCH](#)
[IEEE XPLORE GUIDE](#)

Results for "(['integrated circuit' and simulat* and 'state space')<in>metadata)"

e-mail

Your search matched 22 of 1222090 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Publication year in Descending order.

» Search Options

[View Session History](#)
[New Search](#)

Modify Search


☐ Check to search only within this results set
Display Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

Select Article Information

- ☐ 1. **Time-domain simulation of sampled weakly nonlinear systems using ana integration and orthogonal polynomial series [mixed-signal IC application]**
Martens, E.; Gielen, G.;
Design, Automation and Test in Europe, 2005. Proceedings
2005 Page(s):120 - 125 Vol. 1
Digital Object Identifier 10.1109/DATE.2005.311
[AbstractPlus](#) | Full Text: [PDF](#)(168 KB) IEEE CNF
- ☐ 2. **Design and analysis of power-CMOS-gate-based switched-capacitor boot inverter**
Yuen-Haw Chang;
Circuits and Systems I: Regular Papers, IEEE Transactions on [see also Circu Fundamental Theory and Applications, IEEE Transactions on]
Volume 51, Issue 10, Oct. 2004 Page(s):1998 - 2016
Digital Object Identifier 10.1109/TCSI.2004.835681
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(1128 KB) IEEE JNL
- ☐ 3. **Passive reduction algorithm for RLC interconnect circuits with embedder systems (PRESS)**
Saraswat, D.; Achar, R.; Nakhla, M.S.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 52, Issue 9, Part 2, Sept. 2004 Page(s):2215 - 2226
Digital Object Identifier 10.1109/TMTT.2004.834571
[AbstractPlus](#) | Full Text: [PDF](#)(520 KB) IEEE JNL
- ☐ 4. **Study of "tanh" ideal and lossy ELIN integrators**
Bozomitu, R.G.; Burdia, D.; Cehan, V.;
Electronics Technology: Meeting the Challenges of Electronics Technology Pro
27th International Spring Seminar on
Volume 2, 13-16 May 2004 Page(s):177 - 183 vol.2
[AbstractPlus](#) | Full Text: [PDF](#)(269 KB) IEEE CNF
- ☐ 5. **Cost-efficient block verification for a UMTS up-link chip-rate coprocessor**
Winkelmann, K.; Trylus, H.-J.; Stoffel, D.; Fey, G.;
Design, Automation and Test in Europe Conference and Exhibition, 2004. Proc
Volume 1, 16-20 Feb. 2004 Page(s):162 - 167 Vol.1
Digital Object Identifier 10.1109/DATE.2004.1268843
[AbstractPlus](#) | Full Text: [PDF](#)(279 KB) IEEE CNF

- ☐ 6. **A new nonlinear transient modelling technique for high-speed integrated applications based on state-space dynamic neural network**
Cao, Y.; Ding, R.T.; Zhang, Q.J.;
Microwave Symposium Digest, 2004 IEEE MTT-S International
Volume 3, 6-11 June 2004 Page(s):1553 - 1556 Vol.3
Digital Object Identifier 10.1109/MVSYM.2004.1338875
[AbstractPlus](#) | Full Text: [PDF](#)(471 KB) IEEE CNF

- ☐ 7. **Fast and accurate identifying subcircuits using an optimization based technique**
Rubanov, N.;
Signals, Circuits and Systems, 2003. SCS 2003. International Symposium on
Volume 1, 10-11 July 2003 Page(s):69 - 72 vol.1
[AbstractPlus](#) | Full Text: [PDF](#)(338 KB) IEEE CNF

- ☐ 8. **Implicit resolution of the Chapman-Kolmogorov equations for sequential application in power estimation**
Freitas, A.T.; Oliveira, A.L.;
Design, Automation and Test in Europe Conference and Exhibition, 2003
2003 Page(s):764 - 769
Digital Object Identifier 10.1109/DATE.2003.1253699
[AbstractPlus](#) | Full Text: [PDF](#)(367 KB) IEEE CNF

- ☐ 9. **Efficient simulation of interconnects in high-speed circuits**
Dautbegovic, E.; Condon, M.;
High Frequency Postgraduate Student Colloquium, 2003
8-9 Sept. 2003 Page(s):81 - 84
[AbstractPlus](#) | Full Text: [PDF](#)(276 KB) IEEE CNF

- ☐ 10. **Model checking algorithms for analog verification**
Hartong, W.; Hedrich, L.; Barke, E.;
Design Automation Conference, 2002. Proceedings. 39th
10-14 June 2002 Page(s):542 - 547
Digital Object Identifier 10.1109/DAC.2002.1012684
[AbstractPlus](#) | Full Text: [PDF](#)(728 KB) IEEE CNF

- ☐ 11. **Guaranteed passive balancing transformations for model order reduction**
Phillips, J.; Daniel, L.; Miguel Silveira, L.;
Design Automation Conference, 2002. Proceedings. 39th
10-14 June 2002 Page(s):52 - 57
Digital Object Identifier 10.1109/DAC.2002.1012593
[AbstractPlus](#) | Full Text: [PDF](#)(708 KB) IEEE CNF

- ☐ 12. **Specification-driven test generation for analog circuits**
Variyam, P.N.; Chatterjee, A.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction
Volume 19, Issue 10, Oct. 2000 Page(s):1189 - 1201
Digital Object Identifier 10.1109/43.875320
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(288 KB) IEEE JNL

- ☐ 13. **Characterization of a CMOS current-steering DAC using state-space model**
Andersson, K.A.; Wikner, J.J.;
Circuits and Systems, 2000. Proceedings of the 43rd IEEE Midwest Symposium
Volume 2, 8-11 Aug. 2000 Page(s):668 - 671 vol.2
Digital Object Identifier 10.1109/MWSCAS.2000.952845
[AbstractPlus](#) | Full Text: [PDF](#)(288 KB) IEEE CNF

- ☐ **14. Model order reduction of large circuits using balanced truncation**
Rabiei, P.; Pedram, M.;
Design Automation Conference, 1999. Proceedings of the ASP-DAC '99. Asia
18-21 Jan. 1999 Page(s):237 - 240 vol.1
Digital Object Identifier 10.1109/ASPDAC.1999.760004
[AbstractPlus](#) | Full Text: [PDF\(336 KB\)](#) IEEE CNF

- ☐ **15. ftd: an exact frequency to time domain conversion for reduced order RLC models**
Ying Liu; Pileggi, L.T.; Strojwas, A.J.;
Design Automation Conference, 1998. Proceedings
15-19 Jun 1998 Page(s):469 - 472
[AbstractPlus](#) | Full Text: [PDF\(372 KB\)](#) IEEE CNF

- ☐ **16. Automatic netlist extraction for measurement-based characterization of interconnect**
Corey, S.D.; Yang, A.T.;
Microwave Theory and Techniques, IEEE Transactions on
Volume 45, Issue 10, Part 2, Oct. 1997 Page(s):1934 - 1940
Digital Object Identifier 10.1109/22.641796
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(164 KB\)](#) IEEE JNL

- ☐ **17. An easy approach to formal verification**
Schlipf, T.; Buchner, T.; Fritz, R.; Helms, M.;
ASIC Conference and Exhibit, 1997. Proceedings., Tenth Annual IEEE Interna
7-10 Sept. 1997 Page(s):120 - 124
Digital Object Identifier 10.1109/ASIC.1997.616990
[AbstractPlus](#) | Full Text: [PDF\(516 KB\)](#) IEEE CNF

- ☐ **18. On the design of micropower active resonators and oscillators using log-processing**
Ngarmnil, J.; Thanachayanont, A.; Toumazou, C.; Pookaiyaudom, S.;
Electronics, Circuits, and Systems, 1996. ICECS '96., Proceedings of the Thir
International Conference on
Volume 1, 13-16 Oct. 1996 Page(s):207 - 210 vol.1
Digital Object Identifier 10.1109/ICECS.1996.582779
[AbstractPlus](#) | Full Text: [PDF\(348 KB\)](#) IEEE CNF

- ☐ **19. Time domain based modeling of lossy coupled transmission lines by app transfer functions**
Cyrusian, S.;
Circuits and Systems, 1995. ISCAS '95., 1995 IEEE International Symposium
Volume 3, 28 April-3 May 1995 Page(s):1840 - 1843 vol.3
Digital Object Identifier 10.1109/ISCAS.1995.523773
[AbstractPlus](#) | Full Text: [PDF\(264 KB\)](#) IEEE CNF

- ☐ **20. Efficient reduced-order modeling of frequency-dependent coupling induc associated with 3-D interconnect structures**
Silveira, L.M.; Kamon, M.; White, J.;
European Design and Test Conference, 1995. ED&TC 1995, Proceedings.
6-9 March 1995 Page(s):534 - 538
Digital Object Identifier 10.1109/EDTC.1995.470349
[AbstractPlus](#) | Full Text: [PDF\(380 KB\)](#) IEEE CNF

- ☐ **21. A guaranteed stable order reduction algorithm for packaging and interco**
Silveira, L.M.; Elfadel, I.M.; White, J.K.;
Electrical Performance of Electronic Packaging, 1993
20-22 Oct. 1993 Page(s):165 - 168
Digital Object Identifier 10.1109/EPEP.1993.394563

[AbstractPlus](#) | Full Text: [PDF](#)(192 KB) IEEE CNF



22. Neural algorithms for cell placement in VLSI design

Caviglia, D.D.; Bisio, G.M.; Curatelli, F.; Giovannacci, L.; Raffo, L.;
Neural Networks, 1989. IJCNN., International Joint Conference on
18-22 June 1989 Page(s):573 - 580 vol.1

Digital Object Identifier 10.1109/IJCNN.1989.118635

[AbstractPlus](#) | Full Text: [PDF](#)(652 KB) IEEE CNF



Indexed by
 Inspec

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE -